

J-lite and JX-lite Certification

J-lite and JX-lite Certification				
Test	Sample Size	Standard	J-lite (JL)	JX-lite (JXL)
Serialization			Read and Record	Read and Record
Number 1: Electrical Test	100%		25°C (DC1) Per Device Datasheet	25°C, -55°C, 125°C (DC1, DC2, DC3) Per Device Datasheet
Number 2: Temperature Cycling	100%	MIL-STD-750:	10 Cycles	20 Cycles
		TM 1051 Condition B	(-55°C to +125°C)	(-55°C to +125°C)
Number 3: Electrical Test	100%		25°C (DC2) Per Device Datasheet	25°C (DC4) Per Device Datasheet
Number 4: PIND	100%	MIL-STD-750:	-	Applicable
Hermetic Devices Only		2052 Condition A		
Number 5: HTRB	100%	MIL-STD 750:	48 Hours for Diodes. 48 Hours for NPN Transistors. 24 Hours for PNP Transistors. 48 Hours for MOSFETs.	96 Hours for Diodes. 96 Hours for NPN Transistors. 48 Hours for PNP Transistors. 96 Hours for MOSFETs.
		1038-A, 1039-A, 1040-A, 1042-B		
Number 6A: Electrical Test	100%		25°C (DC3) Per Device Datasheet	25°C (DC5) Per Device Datasheet
Number 6B: Delta Shift Calculations	100%		-	Per Specified Parameters on Device Datasheet
Number 6C: PDA Evaluation	100%		-	20% Allowable per Min/Max Limits of Device Datasheet
Number 7: Gross Leak	100%	MIL-STD 750	Performed	Performed
Hermetic Devices Only		1071		
Number 8: Final Electrical Test	100%		25°C (DC4) Per Device Datasheet	25°C, -55°C, 125°C (DC6, DC7, DC8) Per Device Datasheet

J-lite and JX-lite Qualification			
Process	Test Method & Conditions	Failures/Sample Size	
		J-lite (JL)	JX-lite (JXL)
MIL-PRF 19500 Group A		-	-
Subgroup 1: Visual and Mechanical Examination	MIL-STD 750: 2071	0/45	0/45
Subgroup 2: DC Testing @ 25°C	As Per Datasheet	0/116	0/116
Subgroup 3: DC Testing at High and Low Specified Temperatures		0/116	0/116
Subgroup 4: AC Testing @ 25°C		0/116	0/116
Subgroup 5: Safe Operation Area (Transistors Only)		0/45	0/45
Subgroup 6: Surge Current (Diodes/Rectifiers Only)		0/22	0/22
Subgroup 7: Selected Static and Dynamic Tests		0/22	0/22

Note:

- 1) Devices supplied will be to the test flow illustrated above. Any changes to the flow must be agreed upon in writing by the customer and Central Semiconductor Corp.
- 2) Above are the standard Certification and Qualification test flows for all devices starting with JL (for J-lite) and JXL (for JX-lite) devices.

Example:

JL2N2222A = J-lite certified version of a Central Semiconductor 2N2222A

JXL2N2222A = JX-lite certified version of a Central Semiconductor 2N2222A